

PATENT

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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of

Michial Duff Howell et al.

Application No.: NEW

Filed: HEREWITH

For: METHOD AND APPARATUS FOR
PREPARING SEMICONDUCTOR
WAFERS FOR MEASUREMENT

Group Art Unit: Unknown

Examiner: Unknown

**INFORMATION DISCLOSURE
STATEMENT**121 Spear Street, Suite 290
San Francisco, CA 94105
(415) 512-1312

M/S PATENT APPLICATION

Commissioner for Patents

P.O. Box 1450

Alexandria, VA 22313-1450

Sir:

Applicant(s) submit(s) herewith patents, publications or other information [attached hereto and listed on the attached Form PTO-1449 (modified)] of which they are aware, which they believe(s) may be material to the examination of this application and in respect of which there may be a duty to disclose in accordance with 37 CFR § 1.56.

This Information Disclosure Statement:

- (a) ☒ accompanies the new patent application submitted herewith. 37 CFR § 1.97(a).
- (b) ☐ is filed within three months after the filing date of the application or within three months after the date of entry of the national stage of a PCT application as set forth in 37 CFR § 1.491.
- (c) ☐ as far as is known to the undersigned, is filed before the mailing date of a first Office Action on the merits, or before a first office action after filing a Request for Continued Examination under §1.114.
- (d) ☐ is filed after the first office action and more than three months after the application's filing date or PCT national stage date of entry filing but, as far as is known to the undersigned, prior to the mailing date of either a final rejection or a

Atty Docket No.: TWI-8570

notice of allowance, whichever occurs first, and is accompanied by either the fee (\$180) set forth in 37 CFR § 1.17(p) or a certification as specified in 37 CFR § 1.97(e), as checked below.

- (e) ☐ is filed after the mailing date of either a final rejection or a notice of allowance, whichever occurred first, and the Issue Fee has not been paid, and is accompanied by the fee (\$130) set forth in 37 CFR § 1.17(i)(1) and a certification as specified in 37 CFR § 1.97(e), as checked below. This document is to be considered as a petition requesting consideration of the information disclosure statement.

[If either of boxes (d) or (e) is checked above, the following "certification" under 37 CFR § 1.97(e) may need to be completed.] The undersigned certifies that:

- (f) ☐ Each item of information contained in the information disclosure statement was cited in a communication mailed from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of this information disclosure statement.
- (g) ☐ No item of information contained in this information disclosure statement was cited in a communication mailed from a foreign patent office in a counterpart foreign application or, to the knowledge of the undersigned after making reasonable inquiry, was known to any individual designated in 37 CFR § 1.56(c) more than three months prior to the filing of this information disclosure statement.

A list of the patent(s) or publication(s) is set forth on the attached Form PTO-1449 (Modified).

A copy of the items on PTO-1449 (Modified) is supplied herewith:

- (h) ☐ each (i) ☒ none (j) ☐ only those listed below:

Those patent(s) or publication(s) which are marked with an asterisk (*) in the attached form PTO-1449 (Modified) are not supplied because they were previously cited by or submitted to the Office in a prior application no. 09/859,917, filed May 17, 2001, and relied upon in this application for an earlier filing date under 35 U.S.C. § 120.

A concise explanation of relevance of the items listed on form PTO-1449 (Modified) is:

- (k) ☒ not given
- (l) ☐ given for each listed item

- (m) ☐ given for only non-English language listed item(s) [Required]
- (n) ☐ is in the form of an English language copy of a Search Report from a foreign patent office, issued in a counterpart application, which refers to the relevant portions of the references [copy attached].

The Examiner is reminded that a "concise explanation of the relevance" of the submitted items "may be nothing more than identification of the particular figure or paragraph of the patent or publication which has some relation to the claimed invention," MPEP § 609.


While the information and references disclosed in this Information Disclosure Statement may be "material" pursuant to 37 CFR § 1.56, it is not intended to constitute an admission that any patent, publication or other information referred to therein is "prior art" for this invention unless specifically designated as such.

In accordance with 37 CFR § 1.97(g), the filing of this Information Disclosure Statement shall not be construed to mean that a search has been made or that no other material information as defined in 37 CFR § 1.56(a) exists. It is submitted that the Information Disclosure Statement is in compliance with 37 CFR § 1.98 and MPEP § 609 and the Examiner is respectfully requested to consider the listed references.

Respectfully submitted,

STALLMAN & POLLOCK LLP

Dated: July 23, 2003

By: 
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Attorneys for Applicant(s)

INFORMATION DISCLOSURE CITATION <i>(Use several sheets if necessary)</i>	Docket Number (Optional) TWI-8570	Application Number NEW
	Applicant(s) Michial Duff Howell et al.	
	Filing Date HEREWITH	Group Art Unit Unknown

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE
	*AA	3,887,392	06/03/1975	Tang	134	1	11/23/1973
	*AB	4,032,750	06/28/1997	Hurko	219	464	03/26/1976
	*AC	5,049,816	09/17/1991	Moslehi	324	158	05/31/1990
	*AD	5,252,807	10/12/1993	Chizinsky	219	390	10/23/1991
	*AE	5,261,965	11/16/1993	Moslehi	134	1	08/28/1992
	*AF	5,306,671	04/26/1994	Ogawa et al.	437	225	06/21/1991
	*AG	5,374,594	12/20/1994	van de Ven et al.	437	247	01/22/1993
	*AH	5,439,596	08/08/1995	Ohmi et al.	210	748	07/02/1992
	*AI	5,449,411	09/12/1995	Fukuda et al.	118	723 MP	10/19/1993
	*AJ	5,589,421	12/31/1996	Miyashita et al.	437	225	09/01/1994
	*AK	5,716,207	02/10/1998	Mishina et al.	432	253	07/26/1996
	*AL	5,798,837	08/25/1998	Aspnes et al.	356	369	07/11/1997
	*AM	5,897,710	04/27/1999	Sato et al.	427	8	04/07/1998
	*AN	5,935,768	08/10/1999	Biche et al.	430	401	06/10/1997
	*AO	6,056,544	05/02/2000	Cho	432	249	04/29/1999
	*AP	6,286,230	09/11/2001	White et al.	34	403	09/07/1999

FOREIGN PATENT DOCUMENTS

	REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
	*AQ	4-357836	06/04/1991	Japan (translation included)	H01L	21/304	X	
	*AR	0 462 459	06/07/1991	EPC	H01L	21/00		
	*AS	04357823	12/10/1992	Japan (Abstract)	H01L	21/027		
	*AT	WO 95/00681	01/05/1995	PCT	C23G	1/00		
	*AU	10-137704	11/08/1996	Japan (w/o translation)	B08B	3/12		X
	*AV	WO 98/05066	02/05/1998	PCT	H01L	21/66		
	*AW	WO 99/02970	01/21/1999	PCT	G01N	21/21		
	*AX	WO 99/356677	07/15/1999	PCT	H01L	21/306		

OTHER DOCUMENTS

(Including Author, Title, Date, Pertinent Pages, Etc.)

	*AY	K. Imen, S.J. Lee & S.D. Allen, "Laser-assisted micron scale particle removal," <i>Appl. Phys. Lett.</i> , Vol 58, No. 2, 14 January 1991, pp. 203-205.
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Examiner	Date Considered
Examiner: Initial if citation considered, whether or not citation is in conformance with MPEP Section 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	